

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner ABDULLAH RIYAMI		Art Unit 2474	Page 1 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0057657 A1	05-2002	LA PORTA et al.	370/331
*	B	US-2002/0105956 A1	08-2002	Saito, Shin	370/401
*	C	US-2002/0126665 A1	09-2002	Ueno, Tsukasa	370/389
*	D	US-2002/0142771 A1	10-2002	Saifullah et al.	455/436
*	E	US-2002/0191562 A1	12-2002	Kumaki et al.	370/331
*	F	US-2002/0191627 A1	12-2002	Subbiah et al.	370/428
*	G	US-6,496,704 B2	12-2002	Yuan, Ruixi	455/466
*	H	US-2003/0012179 A1	01-2003	Yano et al.	370/352
*	I	US-2003/0016844 A1	01-2003	Numaoka, Chisato	382/100
*	J	US-2003/0087646 A1	05-2003	Funato et al.	455/456
*	K	US-2003/0093560 A1	05-2003	Ono et al.	709/244
*	L	US-2003/0161287 A1	08-2003	Venkitaraman et al.	370/338
*	M	US-2003/0182445 A1	09-2003	Smith et al.	709/238

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner ABDULLAH RIYAMI		Art Unit 2474	Page 2 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0196115 A1	10-2003	Karp, Alan H.	713/201
*	B	US-6,654,607 B1	11-2003	Shobatake et al.	455/433
*	C	US-2003/0225912 A1	12-2003	Takeda et al.	709/246
*	D	US-2004/0010615 A1	01-2004	Ernst et al.	709/238
*	E	US-2004/0015607 A1	01-2004	Bender et al.	709/238
*	F	US-2004/0013111 A1	01-2004	Faccin, Stefano	370/378
*	G	US-2004/0063402 A1	04-2004	Takeda et al.	455/041.1
*	H	US-2004/0082312 A1	04-2004	O'Neill et al.	455/405
*	I	US-2004/0100951 A1	05-2004	O'Neill, Alan	370/389
*	J	US-2004/0105420 A1	06-2004	Takeda et al.	370/349
*	K	US-2004/0114554 A1	06-2004	Okajima et al.	370/329
*	L	US-2004/0137888 A1	07-2004	Ohki, Masahiro	455/417
*	M	US-2004/0158639 A1	08-2004	Takusagawa et al.	709/229

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner ABDULLAH RIYAMI		Art Unit 2474	Page 3 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0203740 A1	10-2004	Won et al.	455/426.1
*	B	US-2004/0205211 A1	10-2004	Takeda et al.	709/230
*	C	US-2004/0203596 A1	10-2004	Sreemanthula et al.	455/411
*	D	US-2004/0213260 A1	10-2004	Leung et al.	370/395.3
*	E	US-2004/0205235 A1	10-2004	Matsuhira, Naoki	709/238
*	F	US-2004/0258008 A1	12-2004	Inoue et al.	370/312
*	G	US-6,845,094 B1	01-2005	Zhang, Greg	370/349
*	H	US-2005/0020265 A1	01-2005	Funabiki et al.	455/436
*	I	US-2005/0088994 A1	04-2005	Maenpaa et al.	370/331
*	J	US-2005/0078635 A1	04-2005	Choi et al.	370/331
*	K	US-2005/0111377 A1	05-2005	Lioy et al.	370/252
*	L	US-2005/0147062 A1	07-2005	Khouaja et al.	370/332
*	M	US-6,957,262 B2	10-2005	Kimura et al.	709/227

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner ABDULLAH RIYAMI		Art Unit 2474	Page 4 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0226197 A1	10-2005	Reddy et al.	370/338
*	B	US-6,965,584 B2	11-2005	Agrawal et al.	370/331
*	C	US-2005/0272438 A1	12-2005	Holur et al.	455/452.2
*	D	US-2005/0271034 A1	12-2005	Asokan et al.	370/349
*	E	US-2006/0010250 A1	01-2006	Eisl et al.	709/245
*	F	US-2006/0013170 A1	01-2006	Shin et al.	370/338
*	G	US-2006/0062214 A1	03-2006	Ng et al.	370/389
*	H	US-7,039,035 B2	05-2006	Droms et al.	370/338
*	I	US-7,123,599 B2	10-2006	Yano et al.	370/331
*	J	US-2006/0276209 A1	12-2006	Neves et al.	455/466
*	K	US-2007/0005971 A1	01-2007	Leung et al.	713/171
*	L	US-2007/0105555 A1	05-2007	Miernik et al.	455/435.1
*	M	US-7,215,668 B2	05-2007	Saito, Shin	370/392

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
	Examiner ABDULLAH RIYAMI		Art Unit 2474	Page 5 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,251,238 B2	07-2007	Joshi et al.	370/338
*	B	US-7,289,504 B1	10-2007	Hippelainen et al.	370/392
*	C	US-2008/0013487 A1	01-2008	Molteni et al.	370/329
*	D	US-7,362,756 B2	04-2008	Choi et al.	370/389
*	E	US-7,453,842 B2	11-2008	Yamamoto, Junji	370/328
*	F	US-7,593,362 B1	09-2009	Casati et al.	370/328
*	G	US-2003/0084293	05-2003	Arkko et al.	713/168
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.